## Applicant(s)/Patent Under Application/Control No. Reexamination 10/615,956 LEE ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1773 Kevin M Bernatz **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 428/611 10-2002 Ikeda et al. Α US-6,468,670 428/694.0ML 12-2001 Kikitsu et al. US-2001/0051287 В 428/694.0TM 12-2002 С US-2002/0192506 Coffey et al. 428/611 US-6,709,768 03-2004 Takahashi et al. D E US-US-F US-G Н US-US-US-J Κ US-L US-US-М **FOREIGN PATENT DOCUMENTS** Document Number Date Name Classification Country Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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